

ESREF 2018 Conference

Provisional Programme

Ver. 04 - 15-05-2018

Monday, October 1						Tuesday, October 2						Wednesday, October 3						Thursday, October 4						Friday, October 5			
Room A	Room B	Room C	Room D	Exhibition area		Room A	Room B	Room C	Room D	Exhibition area		Room A	Room B	Room C	Room D	Exhibition area	Room A	Room B	Room C	Room D	Exhibition area						
	TUTORIAL Reliability issues in power SiC and GaN		EFUG Workshop	Exhibition set up		E1-2 (5)	A-1 (5)	K-2 (5)	Industrial session	Exhibition		E2-3 (4)	L-1 (4)	SS1-1 (4)	Industrial session	Exhibition	C-2 (5)	I-1 (5)	G (5)	ECPE Workshop	Exhibition						
		TUTORIAL Diodes: reliability in microelectronics				Invited J. Stathis				Coffee break		Invited F. Altmann	Invited M.B. Taboos			Coffee break					Coffee break						
	TUTORIAL Reliability of packages for power devices					E1-3 (3)	A-2 (3)	B1-1 (3)	Industrial session	Exhibition		F-2 (4)	L-2 (4)	SS1-2 (4)	Workshop: Reliability in innovative Automotive ICs	Exhibition	C-3 (5)	I-2 (5)	D (5)	Workshop: Condition and health monitoring	Exhibition						
				Lunch						Lunch						Lunch	Closing Session										
	TUTORIAL Measure Modeling in Complex Systems	TUTORIAL Introduction to the modern reliability		Exhibition set up		Invited J. Lutz	Invited N. Stojadinovic	B1-2 (3) B2 (1)	Industrial session	Exhibition		Invited R. Amst	Invited P. Pfaff					APETT Symposium				Exhibition dismantling					
	Keynote P. Gargini					E2-1 (5)	A-3 (5)	Best Paper IFRS		Coffee break		F-3 (5)	L-3 (4)	SS1-3 (5)	Workshop: Applied robustness validation	Exhibition						Coffee break					
	Keynote P.C. Kjaer					E2-2 (4)	H (4)	Best Paper IIRA	Industrial session	Exhibition							APETT Symposium					Exhibition dismantling					
	E1-1 (3)	F-1 (3)	C-1 (3)	K-1 (3)	Exhibition set up			B3 (3)				Tour & Social dinner															
				Aalborg City buffet		Poster session																					
						Young Professional Reception																					

- Tracks**
- A - Quality and Reliability Assessment Techniques and Methods for Devices and Systems
 - B1 - Si-Technologies & Nanoelectronics: Hot Carriers, High-K, Gate Materials
 - B2 - Si-Technologies & Nanoelectronics: Low-K, Cu Interconnects
 - B3 - Si-Technologies & Nanoelectronics: ESD, EMI and Latch-up
 - C - Progress in Failure Analysis: Defect Detection and Analysis
 - D - Reliability of Microwave and Compound Semiconductors Devices
 - E1 - Power Devices Reliability - Silicon and Passive
 - E2 - Power Devices Reliability - Wide Bandgap Devices
 - F - Packaging and Assembly Reliability
 - G - MEMS, Sensors and Organic Electronics Reliability
 - H - Photonics Reliability
 - I - Extreme Environments and Radiation
 - K - Renewable Energies Reliability
 - L - Modeling for Reliability
 - SS1 - Reliability in Traction Applications